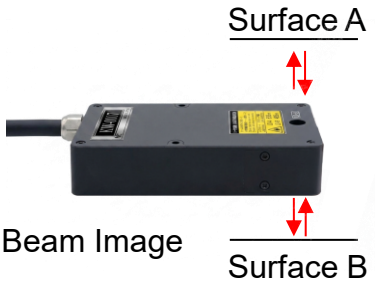
New Technology for Accurate Separation and Identification of Overlapping Spots Using a Parallelism Sensor

KATSURA OPTO SYSTEMS

CSP0228EN-2_260703

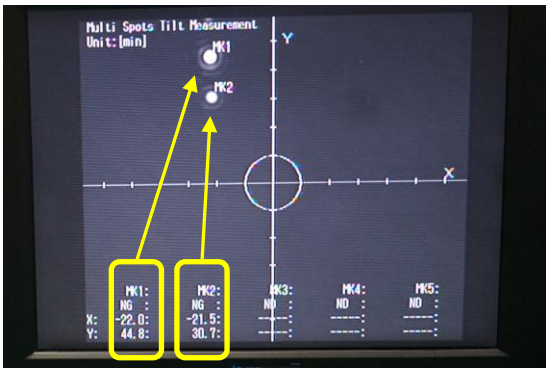
Parallelism Sensor



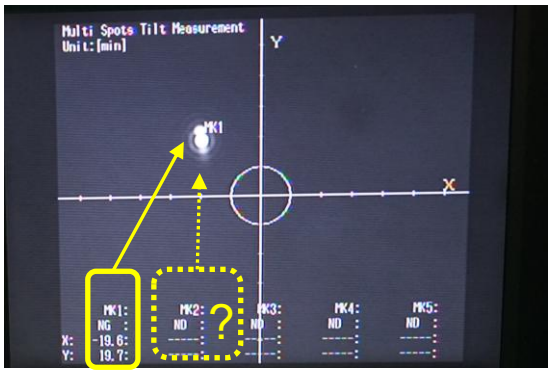
Beam Image

Limitations of Conventional Methods

When the angular deviation between Surface A and Surface B was small, the two reflected spots overlapped, making it difficult to accurately distinguish them.



When the spots are sufficiently separated, they can be correctly identified as two individual spots.

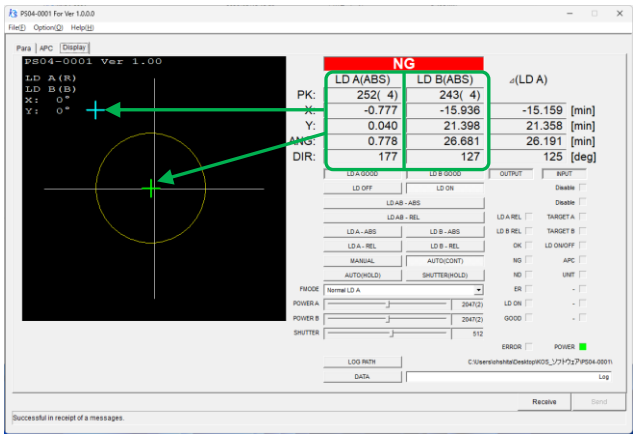


However, when the spots are close to each other or overlap, they may be recognized as one single spot.

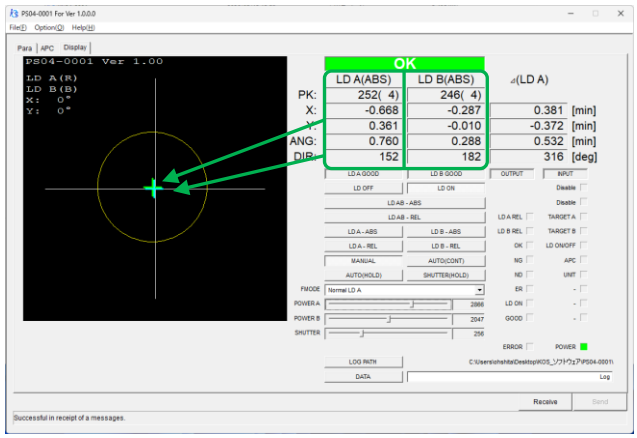
Measurement Error

Solved by New Technology

Our new technology enables accurate identification of each reflected spot, even when the reflected spots overlap.



When the spots are sufficiently separated, they can be correctly identified as two individual spots.



Even when the spots are close to each other or overlap, they can be accurately identified as two individual spots.